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**National figures in DNA testing to speak at conference  
in Dayton directed by Wright State faculty member**

**4-000**

National DNA experts from such high profile cases as O.J. Simpson, Scott Peterson and Ted Kaczynski will speak at the Third Annual Forensic Bioinformatics Conference in Dayton from Friday, Aug. 20, through Sunday, Aug. 22.

Dan Krane, Ph.D., an associate professor of biological sciences at Wright State University and nationally recognized expert on DNA testing, will direct the conference at the University of Dayton School of Law.

“DNA from Crime Scene to Court Room: An Expert Forum” is the title of the event that is expected to attract 300 lawyers, legal experts and forensic scientists.

“This conference will cover all aspects of DNA testing and interpretation and will be of particular interest for defense attorneys,” explained Krane. “DNA experts who are the movers and shakers will explain the issues they face in cases today, as well as cutting edge research.”

The conference is a joint presentation of Wright State University, the University of Dayton School of Law and Forensic Bioinformatics, Inc., a DNA testing firm directed by Krane.

Conference topics on forensic DNA include evidence collection, quality assurance, validation of laboratory procedures, juror comprehension and expert witness selection.

Speakers include Krane, an expert witness in some 50 cases; Robert Blasier, a California defense lawyer who worked on the Simpson and Kaczynski cases; William Shields, a State University of New York professor who has testified in the Peterson murder trial; and Bruce Wier, a North Carolina State University professor who testified at the Simpson trial.

For more details on the conference and registration information visit the Web site [www.bioforensics.com](http://www.bioforensics.com) or contact Krane at [dan.krane@wright.edu](mailto:dan.krane@wright.edu) or (937) 775-2257.

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